

BACK-END

IGBT

DIODE

SEMICONDUCTOR TEST SYSTEM 半導体テストシステム

CHT3010ZZD

3000V
1000A

- CHT3010ZZD is 3000V, 1000A Max DC test system dedicated to IGBT measurement. This system is equipped with a scanner for multi-chip measurement and is a powerful asset as a production tool.
- CHT3010ZZD は IGBT 測定専用で 3000V, 1000A Max の DC テストシステムです。多素子の測定に対応したスキャナを装備し生産設備として威力を発揮します。

MODEL	CHT3010ZZD
SOFTWARE	
TEST PLAN/SORT PLAN	1000/1000
BIN OUT	24
MEASURABLE DEVICES	IGBT, DIODE
VOLTAGE/CURRENT	3000V/1000A
PROGRAMABLE SCANNER	POWER LINE...16pin CONTROL LINE...32pin
TEST ITEMS	
IGBT	ICES, BV _{CES} , I _{GES} , GShock, BV _{GES} , V _{TH} , V _{CE(SAT)} , V _{FECS} , R _{TH} , VR _{TH} , V _{CE(SAT)} , I _{CE(SAT)}
DIODE	I _R , B _V R, V _F
DIMENSIONS & WEIGHT	
MAIN UNIT	550(W)×1060(D)×1700(H)…290kg



Software Display(Scanner Setting)

